# 論文の内容の要旨

Photo-induced charge transfer in [Ar-N<sub>2</sub>]<sup>+</sup> and electron diffraction of CCl<sub>3</sub><sup>+</sup> by ion trap (イオントラップによる[Ar-N<sub>2</sub>]<sup>+</sup>の光誘起電荷移動 および CCl<sub>3</sub><sup>+</sup>の電子回折)

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#### I. Introduction

By trapping molecular ions in a Paul-type quadrupole ion trap, we are able to investigate spectroscopic properties of single ion species as well as unimolecular reaction processes starting from single ion species. When ion complexes  $[A \cdots B]^+$  are trapped in an ion trap, its photo-excitation will give us an opportunity to investigate a charge transfer reaction within the complex, leading to two different products, that is,  $A + B^+$  and  $A^+ + B$ . In my thesis study, I investigate the mechanism of intermolecular charge transfer processes in  $[A \cdots N_2]^+$  induced by intense femtosecond near-IR laser fields by ion-trap time-of-flight (TOF) mass spectrometry and show that non-adiabatic couplings among the potential energy curves of the electronic states play a crucial role in the charge transfer reactions, producing the product pairs of  $Ar + N_2^+$  and  $Ar^+ + N_2$ .

On the other hand, it has been known that geometrical structures of molecular ions can be determined by electron diffraction measurements of molecular ions trapped in a Paul-type quadrupole ion trap and the distances between neighboring nuclei in highly symmetric large size clusters such as  $C_{60}^+$  [1] and  $Ru_{20}^-$  [2] were estimated. However, it has been an extremely difficult task to determine geometrical structures of fundamental and small-sized molecular ions by the ion-trap gas electron diffraction method because the density of the molecular ions in an ion trap could not be higher than  $10^7$  molecules/cm<sup>3</sup>, which is comparable with the density of background gas species in a vacuum chamber. In my thesis study, I developed an apparatus of an ion-trap electron diffraction and succeeded in recording an electron diffraction pattern that the geometrical structures are consistent with those obtained by the previous theoretical predictions.

### II. Photo-induced charge transfer in $[Ar \cdots N_2]^+$

The electronic ground state of  $[Ar \cdots N_2]^+$ , having the electron configuration of  $Ar({}^1S) \cdots N_2^+(X \,{}^2\Sigma_g^+)$  and the first and second electronically excited states of  $[Ar \cdots N_2]^+$ , having the electron configuration of  $Ar^+({}^2P_{3/2}) \cdots N_2(X^{1}\Sigma_g^+)$  and  $Ar^+({}^2P_{1/2}) \cdots N_2(X^{1}\Sigma_g^+)$ , are strongly mixed in the molecular domain as represented by the overlapping potential energy curves shown in Fig. 1. It has been reported [4,5] that, after the irradiation of visible and UV laser pulses,  $[Ar \cdots N_2]^+$  is photodissociated through the two pathways via the first electronically excited state of  $[Ar \cdots N_2]^+$ :

$$Ar'({}^{2}P_{3/2}) \cdots N_{2} (X^{1}\Sigma_{g}) \to Ar'({}^{2}P_{3/2}) + N_{2} (X^{1}\Sigma_{g}),$$
(1)

$$Ar^{+}(^{2}P_{3/2})\cdots N_{2}(X^{1}\Sigma_{g}^{+}) \to Ar(^{1}S) + N_{2}^{+}(X^{2}\Sigma_{g}^{+})$$
(2)

and that the yield ratio of the charge transfer pathway,  $\gamma$ , defined as

$$y = \frac{I(N_2^+)}{I(Ar^+) + I(N_2^+)}$$
(3)

is in the range of  $\gamma = 0.15 \sim 0.25$  when the wavelength of the laser pulses is in the range of 650~270 nm, where  $I(Ar^+)$  denotes the yield of Pathway (1) and  $I(N_2^+)$  denotes the yield of Pathway (2).

In my thesis study,  $[Ar \cdots N_2]^+$ , prepared selectively in the Paul-type quadrupole ion trap, is irradiated with ultrashort near-IR (800 nm) laser pulses, and the resultant fragment on species are detected by time-of-flight mass spectrometry. On the basis of the excitation energy dependence of  $\gamma$ , the mechanism of the charge transfer reaction processes is investigated. The  $[Ar \cdots N_2]^+$  complexes formed by the collisions of  $Ar^+$  and  $N_2^+$ , which are generated through the multiphoton

ionization by the irradiation of femtosecond near-IR intense laser pulses ( $\lambda = 800 \text{ nm}$ ,  $\Delta t = 40 \text{ fs}$ ,  $I = 1.9-3.1 \times 10^{14} \text{ W/cm}^2$ , 5 kHz), with neutral Ar and N<sub>2</sub> are exclusively stored in the ion trap by the stored waveform inverse Fourier transform (SWIFT) method [6]. The trapped [Ar···N<sub>2</sub>]<sup>+</sup> complexes are irradiated with the femtosecond intense laser pulses, and immediately after the irradiation, the fragment ions, Ar<sup>+</sup> and N<sub>2</sub><sup>+</sup>, and the remaining [Ar···N<sub>2</sub>]<sup>+</sup> complexes are extracted by the pulsed voltage applied to the cap electrodes of the ion trap into the TOF tube for the mass resolved ion detection. From the yield of the Ar<sup>+</sup> originating from Pathway (1) and that of the N<sub>2</sub><sup>+</sup> signals originating from Pathway (2),  $\gamma$  is determined to be  $\gamma = 0.62(2)$ .

As shown in Fig. 2, this  $\gamma$  value is found to be about three times as large as the  $\gamma$  values obtained in the previous studies [4,5] in which the excitation photon energies are higher than 1.91 eV. In order to interpret the excitation photon energy dependence of  $\gamma$ , I performed numerical simulations of the statistical population transfer through the potential crossings using the Landau-Zener-Stückelberg (LZS) model [7-9]. The broken line in Fig. 2 is the result of the numerical simulation of the yield ratio of N<sub>2</sub><sup>+</sup> as a function of the excitation photon energy. In the larger photon energy (hv > 1.91 eV), the yield ratio of N<sub>2</sub><sup>+</sup> is in good agreement with the previous experimental results. However, there is a significant discrepancy between the results obtained by the numerical simulation and the experimental result at hv = 1.55 eV recorded in the present study. In order to explain the discrepancy, I included the dissociation processes via the intramolecular vibrational energy transfer occurring on the potential energy curve correlating with  $Ar + N_2^+$  ( $v \ge 1$ ). The solid line in Fig. 2 is the result of the numerical simulation, exhibiting a good agreement with the experimental result at hv = 1.55 eV, confirming that the vibrational energy stored in N<sub>2</sub><sup>+</sup> is transferred to the motion along the dissociation coordinate, that is, the efficient V-T energy transfer proceeds.



Fig. 1. The potential energy curves of the low-lying electronic states of  $[Ar \cdots N_2]^+$  in the linear geometry drawn based on Ref. 3, as a function of the distance *R*.



Fig. 2. The yield ratio of  $N_2^+$  as a function of the excitation photon energy calculated by the LZS model (broken line) and the V-T energy transfer model (solid line). circle: present study, open triangles: Ref. 4, and open squares: Ref. 5.

#### III. Determination of geometrical structure of CCl<sub>3</sub><sup>+</sup>

A schematic of the experimental setup of the ion-trap electron diffraction is shown in Fig. 3. The apparatus is composed of a 20 keV electron gun, a Paul-type ion trap, a two-dimensional delay-line detector (DLD) having a central hole (6.4 mm $\phi$ ), a pulsed valve (200 Hz). From the pulsed valve, a sample gas (CCl<sub>4</sub>) is injected into the ion trap and CCl<sub>3</sub><sup>+</sup> is generated by dissociative ionization induced by a near-IR femtosecond laser pulse (5 kHz,  $\lambda = 800$  nm,  $\Delta t = 40$  fs,  $I = 8.0 \times 10^{14}$  W/cm<sup>2</sup>). The generated CCl<sub>3</sub><sup>+</sup>, which is mass-selectively trapped in the center of the ion trap, is irradiated with an electron beam accelerated to 20 keV. The electron scattering signals are detected by DLD and unscattered electrons, passing through the central hole of the DLD, are trapped by a Faraday cup. In order to reduce background signals originating from stray electrons, a diaphragm with a stainless steel tube  $(4 \text{ mm}\phi)$  is placed between the DLD and the ion trap and two Neodymium magnets are placed closed to the Faraday trap. Owing to the reduction of the background electron signals, it became possible to detect electrons scattered by trapped CCl<sub>3</sub><sup>+</sup> with a count rate of 20 cps.

In Fig. 4, the angular distribution of the scattered electrons, I(s), is shown with red dots as a function of the scattering parameter *s* defined as

 $s = \frac{4\pi}{\lambda} \sin \frac{\theta}{2}$ , where  $\lambda$  denotes the de Broglie wavelength of electrons and

 $\theta$  denotes the scattering angle. The thin solid curve is a smooth background curve,  $I_{\rm B}(s)$ , drawn so that the molecular scattering curve, sM(s), can be extracted, where sM(s) is defined as  $(I(s) - I_{\rm B}(s))/I_{\rm B}(s)$ . The resulting molecular scattering curve is shown in Fig. 5 with dots. The dotted curve is sM(s) calculated using the structural parameters of  $r_{\rm e}({\rm C-Cl}) = 1.6501$  Å,  $r_{\rm e}({\rm Cl}\cdots{\rm Cl}) = 2.8581$  Å obtained by theoretical MO calculations [10]. In the calculation of sM(s), it was assumed that takes planer geometry and the mean amplitudes of these atom pairs are 0.12 Å. The good agreement between the observed sM(s) and the theoretical sM(s) show that geometrical structures of molecular ions can be determined with high precision by the ion-trap electron diffraction apparatus.

## Skimmer Laser Aperture Electron gun Lon trap

Fig. 3. Schematic of the ion-trap electron diffraction apparatus



Fig. 4. The recorded electron scattering intensity I(s) (dots) as a function of *s* and the background curve  $I_{\rm B}(s)$  (solid line).



Fig. 5. The recorded (dots) and calculated (broken line) molecular scattering intensities, sM(s), of  $CCl_3^+$ .

#### References

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